





Stuttgart Atomic Resolution Microscopy Symposium

15 - 16 December 2014





MAX-PLANCK-GESELLSCHAFT

StAR-M 2014 Programme



Monday 15 December

8:00-10:00 Registration

9:00 Reception

10:00-11:00 Inauguration Ceremony for the JEOL ARM200F TEMs at StEM Welcoming Addresses

11:00-12:30 Scientific Programme

H. Sawada High Resolution Imaging by Aberration Corrected Microscopy M. Haider

Advanced Instrumentation for High Resolution TEM and STEM N. Browning

Quantitative In-Situ (S)TEM and DTEM: From High Spatial Resolution to High Temporal Resolution

12:30-14:00 Lunch and TEM Lab Tours

14:00-15:30 Scientific Programme

Q. Ramasse Atom-by-Atom Characterization and Defect Engineering in Low-Dimensional Materials

A. Kirkland

Structural Studies of Defects and Defect Dynamics in Graphene J. Meyer

Recent Developments in the Manipulation and Analysis of Radiation Sensitive 2-D Materials

15:30-16:00 Coffee Break and TEM Lab Tours

16:00-17:30 Scientific Programme

K. Suenaga

Low Voltage Electron Microscopy for Single Atom Spectroscopy J. Etheridge

Quantitative STEM - Development of Methods and Applications to Materials Problems C. Koch

Multiple-Scattering Assisted Electron Microscopy

18:00 Symposium Dinner

StAR-M 2014 Programme



Tuesday 16 December

9:00-10:30 Scientific Programme

P. Batson

Plasmonic Response and Forces in Sub-Nanoscale Objects

G. Botton

EELS at High Energy/Spatial Resolution for Plasmonics and Oxides with Highly-Correlated Electrons

M. Kociak

Nanoscale Optics with Fast Electrons?

10:30-11:00 Coffee Break and TEM Lab Tours

11:00-12:30 Scientific Programme

M. Watanabe Theoretical Approaches for Quantification of Atomic Resolution X-ray Maps in Aberration-Corrected STEM

P. Schattschneider

EMCD - Magnetic Chiral Dichroism in the Electron Microscope J. Verbeeck

Progress and Challenges in Electron Vortex Research

12:30-14:00 Lunch and TEM Lab Tours

14:00-15:30 Scientific Programme

R. Dunin-Borkowski

Towards Three-Dimensional Characterization of Magnetic Moments Inside Individual Nanocrystals in the TEM

M. Lehmann

Methodical Progress in Electron Holography M. Hytch

In-Situ Electron Holography for the Measurement of Fields

15:30-16:00 Coffee Break and TEM Lab Tours

16:00-17:30 Scientific Programme

S. Pennycook

STEM-EELS Imaging of Complex Oxides

J. Mayer

How can Atomic Resolution TEM Contribute to the Development of New Steels?

Closing Remarks

A CONTRACTOR